	Search Notes		

Application/Control No.	Applicant(s)/Patent und Reexamination	Applicant(s)/Patent under Reexamination	
10/808,829	WEHNER, KATHRYN M.		
Examiner	Art Unit		

2875

Y Quach Lee

	SEAR	CHED	
Class	Subclass	Date	Examiner
362	240 241 294 348 511 517 518	6/7/2005	YMY
	545 547		
	551 555 800		
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INI	ERFERENC	RENCE SEARCHED	
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
NONE	6/7/2005	YMY	